CY54FCT574T, CY74FCT574T 8-BIT REGISTERS WITH 3-STATE OUTPUTS SCCS073 - OCTOBER 2001

 Function, Pinout, and Drive Compatible With FCT and F Logic Reduced V_{OH} (Typically = 3.3 V) Versions of Equivalent FCT Functions 	CY54FCT574T D PACKAGE CY74FCT574T Q OR SO PACKAGE (TOP VIEW)
 Edge-Rate Control Circuitry for Significantly Improved Noise Characteristics 	$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$
 I_{off} Supports Partial-Power-Down Mode Operation 	$ \begin{array}{ccccccccccccccccccccccccccccccccccc$
 Matched Rise and Fall Times Fully Compatible With TTL Input and Output Logic Levels 	$ D_{5} \begin{bmatrix} 7 & 14 \end{bmatrix} O_{5} \\ D_{6} \begin{bmatrix} 8 & 13 \end{bmatrix} O_{6} \\ D_{7} \begin{bmatrix} 9 & 12 \end{bmatrix} O_{7} $
 ESD Protection Exceeds JESD 22 2000-V Human-Body Model (A114-A) 200-V Machine Model (A115-A) 1000-V Charged-Device Model (C101) 	GND [10 11] CP CY54FCT574T L PACKAGE (TOP VIEW)
Edge-Triggered D-Type Inputs	
 250-MHz Typical Switching Rate CY54FCT574T 	$D_{2} \begin{bmatrix} 4 \end{bmatrix} 4^{3} \begin{bmatrix} 2 & 1 & 20 & 19 \\ 1 & 18 \end{bmatrix} O_{1}$
 32-mA Output Sink Current 12-mA Output Source Current 	$ \begin{array}{ccccccccccccccccccccccccccccccccccc$
 CY74FCT574T 64-mA Output Sink Current 32-mA Output Source Current 	D ₅] 7 15 O ₄ D ₆] 8 14 O ₅ 9 10 11 12 13
3-State Outputs	CP CP CP CP

description

The 'FCT574T devices are high-speed, low-power, octal D-type flip-flops, featuring separate D-type inputs for each flip-flop. These devices have 3-state outputs for bus-oriented applications. A buffered clock (CP) and output-enable (\overline{OE}) inputs are common to all flip-flops. The 'FCT574T are identical to 'FCT374T, except for a flow-through pinout to simplify board design. The eight flip-flops in the 'FCT574T store the state of their individual D inputs that meet the setup-time and hold-time requirements on the low-to-high CP transition. When \overline{OE} is low, the contents of the eight flip-flops are available at the outputs. When \overline{OE} is high, the outputs are in the high-impedance state. The state of \overline{OE} does not affect the state of the flip-flops.

These devices are fully specified for partial-power-down applications using I_{off}. The I_{off} circuitry disables the outputs, preventing damaging current backflow through the device when it is powered down.



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PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



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CY54FCT574T, CY74FCT574T **8-BIT REGISTÉRS** WITH 3-STATE OUTPUTS SCCS073 - OCTOBER 2001

TA	PACI	KAGE†	SPEED (ns)	ORDERABLE PART NUMBER	TOP-SIDE MARKING							
	QSOP – Q	Tape and reel	5.2	CY74FCT574CTQCT	FCT574C							
	SOIC – SO	Tube	5.2	CY74FCT574CTSOC	FCT574C							
−40°C to 85°C	3010 - 30	Tape and reel	5.2	CY74FCT574CTSOCT	FG1574C							
	QSOP – Q	Tape and reel	6.5	CY74FCT574ATQCT	FCT574A							
	SOIC – SO	Tube	6.5	CY74FCT574ATSOC	FCT574A							
	3010 - 30	Tape and reel	6.5	CY74FCT574ATSOCT	FG1574A							
	QSOP – Q	Tape and reel	10	CY74FCT574TQCT	FCT574							
	SOIC – SO	Tube	10	CY74FCT574TSOC	FCT574							
	5010 - 50	Tape and reel	10	CY74FCT574TSOCT	FG1574							
	CDIP – D	Tube	6.2	CY54FCT574CTDMB								
–55°C to 125°C	CDIP – D	Tube	7.2	CY54FCT574ATDMB								
	LCC – L	Tube	7.2	CY54FCT574ATLMB								

ORDERING INFORMATION

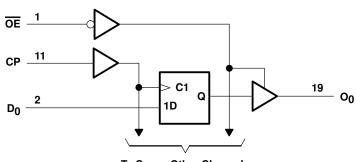
[†] Package drawings, standard packing quantities, thermal data, symbolization, and PCB design guidelines are available at www.ti.com/sc/package.

	FUNC	BLE	
	INPUTS	OUTPUT	
D	СР	OE	0
Н	Ŷ	L	Н
L	Ŷ	L	L
Х	Х	Н	Z

H = High logic level, L = Low logic level, X = Don't care, Z = High-impedance state, X = Non't care, X = N

 \uparrow = Low-to-high clock transition

logic diagram (positive logic)







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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range to ground potential	–0.5 V to 7 V
DC input voltage range	–0.5 V to 7 V
DC output voltage range	–0.5 V to 7 V
DC output current (maximum sink current/pin)	120 mA
Package thermal impedance, θ_{JA} (see Note 1): Q package	68°C/W
SO package	
Ambient temperature range with power applied, T _A	–65°C to 135°C
Storage temperature range, T _{stg}	–65°C to 150°C

† Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: The package thermal impedance is calculated in accordance with JESD 51-7.

recommended operating conditions (see Note 2)

		CY	54FCT57	4T	CY7	74FCT57	'4T	UNIT
		MIN	NOM	MAX	MIN	NOM	MAX	UNIT
V _{CC}	Supply voltage	4.5	5	5.5	4.75	5	5.25	V
VIH	High-level input voltage	2			2			V
VIL	Low-level input voltage			0.8			0.8	V
ЮН	High-level output current			-12			-32	mA
IOL	Low-level output current			32			64	mA
Т _А	Operating free-air temperature	-55		125	-40		85	°C

NOTE 2: All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation.



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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

			CY	54FCT57	'4T	CY			
PARAMETER	TEST CONE	DITIONS	MIN	TYP†	MAX	MIN	TYP†	МАХ	UNIT
M	V _{CC} = 4.5 V, I _{IN} = -18 m/	4		-0.7	-1.2				v
VIK	V _{CC} = 4.75 V, I _{IN} = -18 m/	A					-0.7	-1.2	v
	$V_{CC} = 4.5 \text{ V}, \qquad I_{OH} = -12 \text{ m}$	۱A	2.4	3.3					
VOH	$V_{CC} = 4.75 V$ $I_{OH} = -32 m$	۱A				2			V
	VCC = 4.75 V IOH = -15 m	۱A				2.4	3.3		
Ve	$V_{CC} = 4.5 \text{ V}, \qquad I_{OL} = 32 \text{ mA}$	l l		0.3	0.55				v
V _{OL}	V _{CC} = 4.75 V, I _{OL} = 64 mA	l l					0.3	0.55	v
V _{hys}	All inputs			0.2			0.2		V
	$V_{CC} = 5.5 \text{ V}, \qquad V_{IN} = V_{CC}$				5				μA
Ι	$V_{CC} = 5.25 \text{ V}, V_{IN} = V_{CC}$							5	μА
ЧН	$V_{CC} = 5.5 \text{ V}, \qquad V_{IN} = 2.7 \text{ V}$				±1				μA
	$V_{CC} = 5.25 \text{ V}, \qquad V_{IN} = 2.7 \text{ V}$							±1	μΛ
1	$V_{CC} = 5.5 \text{ V}, \qquad V_{IN} = 0.5 \text{ V}$				±1				μA
ΙL	$V_{CC} = 5.25 \text{ V}, \qquad V_{IN} = 0.5 \text{ V}$							±1	μА
loff	V _{CC} = 0 V, V _{OUT} = 4.5	V			±1			±1	μA
IOS‡	V _{CC} = 5.5 V, V _{OUT} = 0 V		-60	-120	-225				mA
'OS+	V _{CC} = 5.25 V, V _{OUT} = 0 V					-60	-120	-225	IIIA
1071	$V_{CC} = 5.5 \text{ V}, \qquad V_{IN} = 2.7 \text{ V}$				10				μA
IOZH	$V_{CC} = 5.25 \text{ V}, \qquad V_{IN} = 2.7 \text{ V}$							10	μΛ
1071	$V_{CC} = 5.5 \text{ V}, \qquad V_{IN} = 0.5 \text{ V}$				-10				μA
IOZL	$V_{CC} = 5.25 \text{ V}, \qquad V_{IN} = 0.5 \text{ V}$							-10	μΛ
	$V_{CC} = 5.5 \text{ V}, \qquad V_{IN} \leq 0.2 \text{ V},$	$V_{IN} \ge V_{CC} - 0.2 V$		0.1	0.2				mA
ICC	$V_{CC} = 5.25 \text{ V}, \qquad V_{IN} \leq 0.2 \text{ V},$						0.1	0.2	mA
Alee	$V_{CC} = 5.5 \text{ V}, V_{IN} = 3.4 \text{ V}\$, f_1$	= 0, Outputs open		0.5	2				mA
∆ICC	V _{CC} = 5.25 V, V _{IN} = 3.4 V§, f ₁	= 0, Outputs open					0.5	2	mA

[†] Typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$.

* Not more than one output should be shorted at a time. Duration of short should not exceed one second. The use of high-speed test apparatus and/or sample-and-hold techniques are preferable to minimize internal chip heating and more accurately reflect operational values. Otherwise, prolonged shorting of a high output can raise the chip temperature well above normal and cause invalid readings in other parametric tests. In any sequence of parameter tests, IOS tests should be performed last.

§ Per TTL-driven input (V_{IN} = 3.4 V); all other inputs at V_{CC} or GND



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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted) (continued)

				CY	54FCT57	4T	CY	74FCT57	4T	UNIT
PARAMETER		TEST CONDITIONS				МАХ	MIN	түр†	MAX	UNIT
ICCD		utputs open, g at 50% duty cycle IN ≥ V _{CC} – 0.2 V	$\overline{OE} = GND,$		0.06	0.12				mA/
"CCD "		Outputs open, g at 50% duty cycle ′IN [≥] V _{CC} – 0.2 V	$\overline{OE} = GND,$					0.06	0.12	MHz
		One bit switching at f ₁ = 5 MHz	$\begin{array}{l} V_{IN} \leq 0.2 \ V \ or \\ V_{IN} \geq V_{CC} - 0.2 \ V \end{array} \end{array} \label{eq:VIN}$		0.7	1.4				
	$V_{CC} = 5.5 V,$ f ₀ = 10 MHz, <u>Outputs open</u> , $\overline{OE} = GND$	at 50% duty cycle	$V_{IN} = 3.4 \text{ V or GND}$		1.2	3.4				
		Eight bits switching at f ₁ = 2.5 MHz	$\begin{array}{l} V_{IN} \leq 0.2 \ V \ or \\ V_{IN} \geq V_{CC} - 0.2 \ V \end{array} \end{array} \label{eq:VIN}$		1.6	3.2				
1.0		at 50% duty cycle	$V_{IN} = 3.4 \text{ V or GND}$		3.9	12.2				mA
IC		One bit switching at f ₁ = 5 MHz	$\begin{array}{l} V_{IN} \leq 0.2 \ V \ or \\ V_{IN} \geq V_{CC} - 0.2 \ V \end{array} \end{array} \label{eq:VIN}$					0.7	1.4	ШA
	V _{CC} = 5.25 V, f ₀ = 10 MHz,	at 50% duty cycle	$V_{IN} = 3.4 \text{ V or GND}$					1.2	3.4	
	Outputs open, OE = GND	Eight bits switching at f ₁ = 2.5 MHz	$\begin{array}{l} V_{IN} \leq 0.2 \ V \ or \\ V_{IN} \geq V_{CC} - 0.2 \ V \end{array} \end{array} \label{eq:VIN}$					1.6	3.2	
		at 50% duty cycle	$V_{IN} = 3.4 \text{ V or GND}$					3.9	12.2	
Ci					5	10		5	10	рF
Co					9	12		9	12	pF

[†] Typical values are at $V_{CC} = 5 V$, $T_A = 25^{\circ}C$.

¶ This parameter is derived for use in total power-supply calculations.

[#]IC $= I_{CC} + \Delta I_{CC} \times D_H \times N_T + I_{CCD} (f_0/2 + f_1 \times N_1)$

Where:

= Total supply current IC

ICC = Power-supply current with CMOS input levels

 ΔI_{CC} = Power-supply current for a TTL high input (V_{IN} = 3.4 V)

 D_{H} = Duty cycle for TTL inputs high

NT = Number of TTL inputs at DH

I_{CCD} = Dynamic current caused by an input transition pair (HLH or LHL)

= Clock frequency for registered devices, otherwise zero fo

= Input signal frequency f1

N1 = Number of inputs changing at f1

All currents are in milliamperes and all frequencies are in megahertz.

|| Values for these conditions are examples of the I_{CC} formula.



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timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figure 1)

		CY54FCT574T CY54FC			Y54FCT574AT		CY54FCT574CT		
		MIN	MAX	MIN	MAX	MIN	MAX	UNIT	
tw	Pulse duration, CP high or low	7		6		6		ns	
t _{su}	Setup time, data before CP1	2		2		2		ns	
t _h	Hold time, data after CP↑	1.5		1.5		1.5		ns	

timing requirements over recommended operating free-air temperature range (unless otherwise noteď) (see Figure 1)

		CY74FC	T574T	CY74FCT	574AT	CY74FCT	574CT	UNIT
		MIN	MAX	MIN	MAX	MIN	MAX	UNIT
tw	Pulse duration, CP high or low	7		5		5		ns
t _{su}	Setup time, data before CP1	2		2		2		ns
t _h	Hold time, data after CP↑	1.5		1.5		1.5		ns

switching characteristics over operating free-air temperature range (see Figure 1)

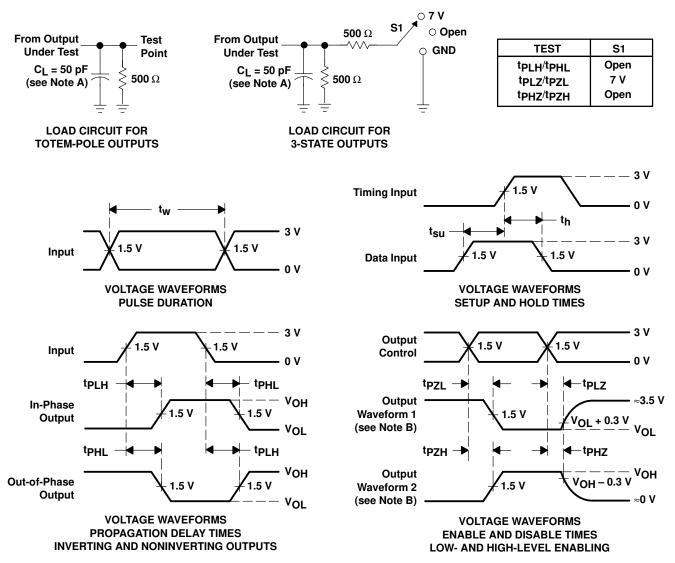
PARAMETER	FROM	то	CY54FC	CY54FCT574T		CY54FCT574AT		CY54FCT574CT		
PARAMETER	(INPUT)	(OUTPUT)	MIN	MAX	MIN	MAX	MIN	MAX	UNIT	
^t PLH	СР	0	2	11	2	7.2	2	6.2	20	
^t PHL	GP	0	2	11	2	7.2	2	6.2	ns	
^t PZH	OE	о	1.5	14	1.5	7.5	1.5	6.2	20	
^t PZL	UE		1.5	14	1.5	7.5	1.5	6.2	ns	
^t PHZ	ŌĒ	0	1.5	8	1.5	6.5	1.5	5.7	20	
^t PLZ	UE	0	1.5	8	1.5	6.5	1.5	5.7	ns	

switching characteristics over operating free-air temperature range (see Figure 1)

PARAMETER	FROM	TO (OUTPUT)	CY74FC	CY74FCT574T		CY74FCT574AT		CY74FCT574CT		
PARAMETER	(INPUT)		MIN	MAX	MIN	MAX	MIN	MAX	UNIT	
^t PLH	СР	0	2	10	2	6.5	2	5.2	ns	
^t PHL	0F	0	2	10	2	6.5	2	5.2	115	
^t PZH	ŌĒ	0	1.5	12.5	1.5	6.5	1.5	5.5	ns	
^t PZL	OE		1.5	12.5	1.5	6.5	1.5	5.5	115	
^t PHZ	ŌĒ	0	1.5	8	1.5	5.5	1.5	5	20	
t _{PLZ}	OE	0	1.5	8	1.5	5.5	1.5	5	ns	



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PARAMETER MEASUREMENT INFORMATION

NOTES: A. C_I includes probe and jig capacitance.

B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.

C. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms





10-Jun-2014

PACKAGING INFORMATION

Orderable Device	Status	Package Type		Pins		Eco Plan	Lead/Ball Finish	MSL Peak Temp	Op Temp (°C)	Device Marking	Samples
	(1)		Drawing		Qty	(2)	(6)	(3)		(4/5)	
5962-9222203M2A	ACTIVE	LCCC	FK	20	1	TBD	POST-PLATE	N / A for Pkg Type	-55 to 125	5962- 9222203M2A CY54FCT 574ATLMB	Samples
5962-9222203MRA	ACTIVE	CDIP	J	20	1	TBD	A42	N / A for Pkg Type	-55 to 125	5962-922203MR A	Samples
5962-9222205MRA	ACTIVE	CDIP	J	20	1	TBD	A42	N / A for Pkg Type	-55 to 125	5962-922205MR A	Samples
CY54FCT574ATLMB	ACTIVE	LCCC	FK	20	1	TBD	POST-PLATE	N / A for Pkg Type	-55 to 125	5962- 9222203M2A CY54FCT 574ATLMB	Samples
CY74FCT574ATQCT	ACTIVE	SSOP	DBQ	20	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 85	FCT574A	Samples
CY74FCT574ATSOC	ACTIVE	SOIC	DW	20	25	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	FCT574A	Samples
CY74FCT574ATSOCG4	ACTIVE	SOIC	DW	20	25	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	FCT574A	Samples
CY74FCT574ATSOCT	ACTIVE	SOIC	DW	20	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	FCT574A	Samples
CY74FCT574CTQCT	ACTIVE	SSOP	DBQ	20	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 85	FCT574C	Samples
CY74FCT574CTSOC	ACTIVE	SOIC	DW	20	25	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	FCT574C	Samples
CY74FCT574CTSOCT	ACTIVE	SOIC	DW	20	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	FCT574C	Samples
CY74FCT574TQCT	ACTIVE	SSOP	DBQ	20	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 85	FCT574	Samples
CY74FCT574TQCTG4	ACTIVE	SSOP	DBQ	20	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 85	FCT574	Samples
CY74FCT574TSOC	ACTIVE	SOIC	DW	20	25	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	FCT574	Samples

⁽¹⁾ The marketing status values are defined as follows: **ACTIVE:** Product device recommended for new designs.





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10-Jun-2014

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect. NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design. PREVIEW: Device has been announced but is not in production. Samples may or may not be available. OBSOLETE: TI has discontinued the production of the device.

⁽²⁾ Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

TBD: The Pb-Free/Green conversion plan has not been defined.

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⁽³⁾ MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

⁽⁴⁾ There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

(⁵⁾ Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

⁽⁶⁾ Lead/Ball Finish - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead/Ball Finish values may wrap to two lines if the finish value exceeds the maximum column width.

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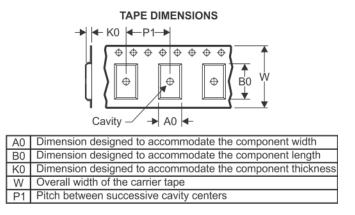
PACKAGE MATERIALS INFORMATION

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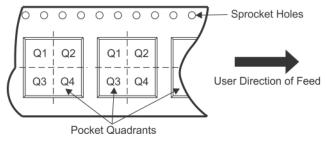
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TAPE AND REEL INFORMATION





QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
CY74FCT574ATQCT	SSOP	DBQ	20	2500	330.0	16.4	6.5	9.0	2.1	8.0	16.0	Q1
CY74FCT574ATSOCT	SOIC	DW	20	2000	330.0	24.4	10.8	13.0	2.7	12.0	24.0	Q1
CY74FCT574CTQCT	SSOP	DBQ	20	2500	330.0	16.4	6.5	9.0	2.1	8.0	16.0	Q1
CY74FCT574CTSOCT	SOIC	DW	20	2000	330.0	24.4	10.8	13.0	2.7	12.0	24.0	Q1
CY74FCT574TQCT	SSOP	DBQ	20	2500	330.0	16.4	6.5	9.0	2.1	8.0	16.0	Q1

TEXAS INSTRUMENTS

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PACKAGE MATERIALS INFORMATION

26-Jan-2013



*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
CY74FCT574ATQCT	SSOP	DBQ	20	2500	367.0	367.0	38.0
CY74FCT574ATSOCT	SOIC	DW	20	2000	367.0	367.0	45.0
CY74FCT574CTQCT	SSOP	DBQ	20	2500	367.0	367.0	38.0
CY74FCT574CTSOCT	SOIC	DW	20	2000	367.0	367.0	45.0
CY74FCT574TQCT	SSOP	DBQ	20	2500	367.0	367.0	38.0

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